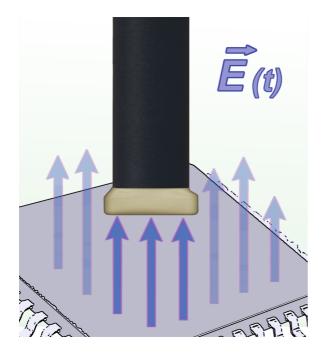
# **SX-E 03** E-Field Probe 1 GHz up to 10 GHz





## Short description

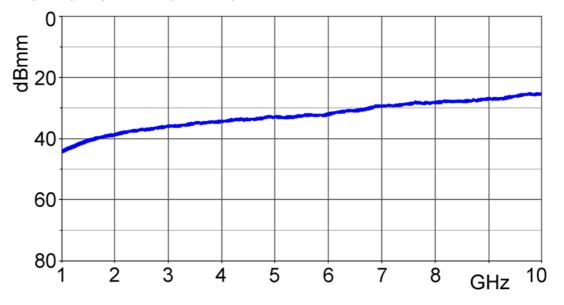
With 4x4 mm dimensions, the electrode on the underside of the probe head of the SX-E 03 is very compact. This allows for the localization of very small E-field sources, e.g. at conducting paths, single components, or on printed circuit boards.

The SX-E 03 is a passive near-field probe. To measure, the probe head is positioned directly onto the measured object, due to higher electrical field strength at the measured object. The near-field probe is small and handy. It has a current attenuating sheath and its upper side is electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a 50  $\Omega$  input.

#### **Technical parameters**

Frequency range	1 GHz 10 GHz
Probe head dimensions:	≈ (4 x 4) mm
Connector - output	SMA, female, jack

Frequency response [dBµV] / [dBµV/mm]

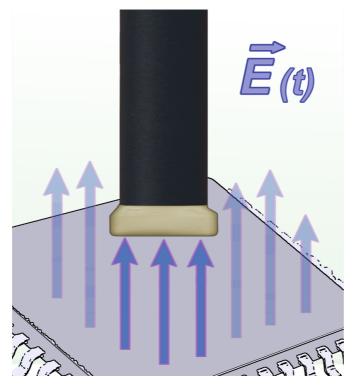


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E- field correction curve [dB $\mu$ V/mm] / [dB $\mu$ V]

Measuring principles



## SX-E 03 E-Field Probe 1 GHz up to 10 GHz



### Probe head

